

Patent Quality Report

The Patent Quality Report allows patent managers to quantitatively assess the technical quality of a patent or patent application at any stage, by simply dragging and dropping a draft of the application, or typing in the publication number of a published application or granted patent. This report includes a numerical grade of the drafting's technical quality, a quantitative breakdown of the different sections of the patent, as well as a comparison of how this application ranks relative to recently granted patents. These analytics are displayed in an easy-to-read format which allows patent managers to quickly assess the quality of their company's patent applications, alerting them to quality issues early in the drafting process so they can take action.



Patent Quality Report

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APPLICATION TITLE

Systems and Methods for Performing Widget Calibration

DOCUMENT ID

US20160012345

Document ID

USPTO patent, application or publication number.

FIRM

Rocinante Law

DOCKET NUMBER

123456

Firm Information

firm, internal docket number, attorney and assignee for the patent.

ATTORNEY

James Holden

ASSIGNEE

Great Corp

QUALITY

34

SCORE

130

TOTAL DEFECTS



SUGGEST REVIEW

Quality Score

this is a high-level summary of the report, which includes a quality score, the total number of defects found in the document and a quick-reference review suggestion. A patent application with a very low quality grade may have a substantially increased risk of rejection, increasing the time and cost of prosecution and increasing the risk that a granted patent may be invalidated during litigation or post-grant review.

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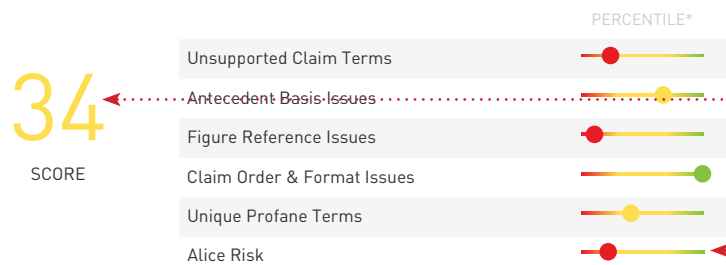
Summary

- Suggest review. Weighted quality metrics are in the median quartile.
- Unsupported claim terms are in the lower quality quartile.
- Figure reference issues are in the lower quality quartile.

Summary

a high-level list of the factors with the largest contribution to a low quality score.

Quality Metrics



* Percentiles are based on a random sample of recently issued patents.

Quality metrics

a graphical representation of where this application ranks relative to a random sampling of recently issued patents, along each of six metrics.

Quality Score

an overall weighted quality grade, out of a possible 100, based on the different issues identified and their relative importance to the technical quality of the patent.

Percentile Rank

the percentile the patent falls into relative to a randomized sampling of recently issued patents.

Content Metrics

CLAIMS

Independent	4	1944	92	81	
Dependent	23				
TOTAL		27	Words	Unique Terms	Elements

Content Metrics

a high-level quantitative overview of the patent, such as the number of figures, and the number of words in each section.

SPECIFICATION

17223 TOTAL WORDS	Background	390	13 Total Figures
	Summary	1176	
	Detailed Description	12879	78 Numbered Items
	Abstract	141	

Art Unit Predictions

Statistics for the five most likely results, in decreasing order

ART UNIT	PERCENT ALLOWED USPTO AVG: 78%	MONTHS TO GRANT USPTO AVG: 38
2648	87%	37 months
2649	85%	38 months
2647	87%	35 months
2633	92%	30 months
2631	92%	30 months

Art Unit Predictions

list of the top five most likely art units listed in decreasing order of likelihood.

Predicted Art Unit

likely art unit (listed in order of likelihood).

Art Unit Allowance Rate

percentage of applications allowed.

Months To Grant

average number of months from filing until an application is granted.

Alice Risk



High



High similarity to business-method subject matter impacted by the Alice decision.

Alice Risk

measures the similarity between this patent and patents pre-dating the supreme court's Alice decision. Applications with a high Alice Risk have a higher likelihood that the application will be rejected as ineligible subject matter under the Alice/Mayo framework. For more information, see: TurboPatent.us/methodology

Alice Related Words

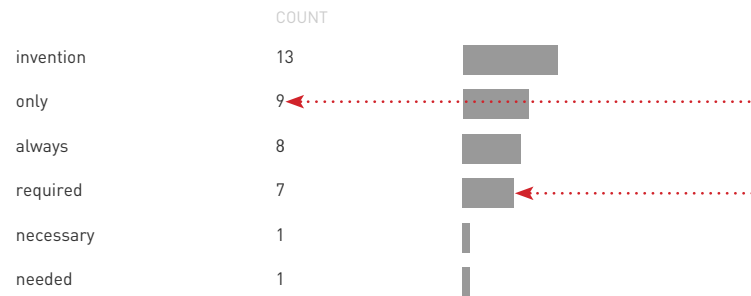
The following words are consistent with abstract/business method subject matter.



Alice Related Words

words which most strongly indicate similarity to patents with abstract business method subject matter.

⚠ Profanity Detected



Profanity Detected

words in the document which may be limiting to the scope of the patent.

Profanity Count

number of occurrences of each profane term.

Profanity Graph

graphical depiction of relative number of occurrences of each profane term.

⚠ Antecedent Basis Issues

CLAIM 1	wireless communications circuitry, gathering radio-frequency performance metric data	unknown antecedent
CLAIM 1	transmitted radio-frequency test signals	unknown antecedent
CLAIM 1	gathered radio-frequency performance metric data	unknown antecedent
CLAIM 3	radio-frequency performance metric data	unknown antecedent
CLAIM 3	amplified radio-frequency test signals	unknown antecedent
CLAIM 4	power amplifier	unknown antecedent; This term appears in Claim 8.
CLAIM 6	transmit signal	unknown antecedent
CLAIM 6	identified transmit voltage level	unknown antecedent
CLAIM 7	power amplifier bias voltage	unknown antecedent
CLAIM 8	identified different power amplifier bias voltages	unknown antecedent

Antecedent Basis Issues

possible antecedent basis issues identified in the claims which could result in a §112 rejection, increasing the cost and time of prosecution.

Claim Term

element which may have been claimed in a manner that may be indefinite.

Antecedent Issue

specific antecedent basis issue encountered.

Claim Number

claim where antecedent basis issue occurred.

✘ Unsupported Claim Terms

The following 24 claim terms were not found in the specification:

CLAIM REFERENCE

corresponding power amplifier bias voltage and output power level	7
first transmit signal and bias voltage calibration data	22
wireless communications circuitry, gathering radio-frequency performance metric data	1
wireless communications circuitry, gathering radio-frequency performance metric information	25
plurality of different power amplifier bias voltages	4
corresponding adjacent channel leakage ratio value	18

Unsupported Claim Terms

elements from the claims which were not found in the specification. This could indicate that the invention was not properly enabled.

Claim Term

noun phrase identified as an element within the claims which is missing from the specification.

Claim Numbers

the list of claims in which each unsupported claim term appears.

⚠ Claim Order & Format Issues

Claim 10	Check line endings in paragraph 2
Claim 20	Check line endings in paragraph 2

Claim Order & Format Issues

a list of possible formatting issues in the claims.

Order or Format Issue

specific issue encountered.

✘ Inconsistent Figure References

The following numbered items are labeled inconsistently in the detailed description:

PART NUMBER	PART NAMES
10	device (94) DUT (41) test (DUT) (1)
16	devices (5) input-output circuitry (1)
18	wireless circuitry (18) wireless communications circuitry (9) circuitry (4) wireless communications devices (1)

Inconsistent Figure References

part numbers of elements which have been referred to inconsistently throughout the document and lists of the part names adjacent to each numbered element as well as the number of times it was referred to by each name.

Part Number

part numbers used when referring to this element within the specification.

Part Count

number of times this part number was referred to by this name.

Nomenclature Table

The following noun phrases were identified in the claims:

	CLAIM REFERENCE
additional entry	24
additional transmit power level	24
adjacent channel leakage ratio value	18
adjustable bias voltage generation circuitry	1, 4, 8, & 12-13
adjustable power supply circuitry	21-22
amplified radio-frequency signals	9 & 14
amplified radio-frequency test signals	3
baseband data	13
baseband processing circuitry	13, 21, & 26
bias voltage calibration data	22-23 & 25
calibration data	1, 6-10, 12-15, & 20
calibration data structure	20 & 23-24
calibration engine	25
common integrated circuit	11
compression value	10
corresponding adjacent channel leakage ratio value	18

Nomenclature Table

a list of noun-phrases which have been identified as possible elements within the invention.

Claim Term

noun phrase identified as an element within the claims.

Claim Numbers

the list of claims in which each claim term appears.

Problem Map

DETAILED-DESCRIPTION

.... The output of transceiver circuitry 48 may be coupled to the input of power amplifier circuitry 46⁴⁹ via path 52. Transceiver circuitry 48 may provide signals to be transmitted to the input of power amplifier circuitry 46⁵⁰ (e.g., transmit signals having a corresponding voltage magnitude V_{in}). Power amplifier circuitry 46⁵¹ (sometimes referred to as a power amplifier circuit or power amplifier) may contain one or more individual power amplifiers (sometimes referred to herein as amplifier stages or gain stages). During data transmission, power amplifier circuitry 46⁵² may boost the output power of transmitted signals TX to a sufficiently high level to ensure adequate signal transmission. For example, power amplifier circuitry 46⁵³ may receive transmit signals from transceiver circuitry 48 having a voltage level V_{in} and a corresponding input power level P_{in} and may output amplified transmit signals TX having an output power level P_{out} (and a corresponding output voltage magnitude V_{out}). The gain provided by power amplifier circuitry 46⁵⁴ may be defined as the ratio of output power level P_{out} to input power level P_{in} .

⁴⁹ inconsistent part name

⁵⁰ inconsistent part name

⁵¹ inconsistent part name

⁵² inconsistent part name

⁵³ inconsistent part name

⁵⁴ inconsistent part name

Problem Map

highlights each term that is the focus of an issue addressed earlier in the report, allowing the reader to quickly locate all of the issues cited within the report.

Problem

issue addressed in the report.

Location

location of the issue within the specification.